



# SLOVENSKI STANDARD

## SIST EN 62810:2015

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### Metoda s valjasto votlino za merjenje kompleksne permitivnosti (dielektrične konstante) nizkoizgubnih dielektričnih palic (IEC 62810:2015)

Cylindrical cavity method to measure the complex permittivity of low-loss dielectric rods (IEC 62810:2015)

Zylindrisches Hohlraumverfahren zur Messung der komplexen Permittivität von verlustarmen dielektrischen Stäben (IEC 62810:2015)

Mesure de la permittivité complexe des barreaux diélectriques à faibles pertes par la méthode de la cavité cylindrique (IEC 62810:2015)

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#### **ICS:**

33.120.30      Radiofrekvenčni konektorji      R.F. connectors  
(RF)

**SIST EN 62810:2015**

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EUROPEAN STANDARD

EN 62810

NORME EUROPÉENNE

EUROPÄISCHE NORM

May 2015

ICS 33.120.30

English Version

## Cylindrical cavity method to measure the complex permittivity of low-loss dielectric rods (IEC 62810:2015)

Mesure de la permittivité complexe des barreaux diélectriques à faibles pertes par la méthode de la cavité cylindrique  
(IEC 62810:2015)

Zylindrisches Hohlraumverfahren zur Messung der komplexen Permittivität von verlustarmen dielektrischen Stäben  
(IEC 62810:2015)

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Comité Européen de Normalisation Electrotechnique  
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Avenue Marnix 17, B-1000 Brussels

## Foreword

The text of document 46F/242/CDV, future edition 1 of IEC 62810, prepared by SC 46F, "R.F. and microwave passive components", of IEC TC 46, "Cables, wires, waveguides, R.F. connectors, R.F. and microwave passive components and accessories" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 62810:2015.

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 NOTE Harmonised as EN 60556.



IEC 62810

Edition 1.0 2015-02

# INTERNATIONAL STANDARD



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**Cylindrical cavity method to measure the complex permittivity of low-loss dielectric rods**

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## INTERNATIONAL ELECTROTECHNICAL COMMISSION

**CYLINDRICAL CAVITY METHOD TO MEASURE  
THE COMPLEX PERMITTIVITY OF LOW-LOSS DIELECTRIC RODS**

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International Standard IEC 62810 has been prepared by subcommittee 46F: R.F. and microwave passive components, of IEC technical committee 46: Cables, wires, waveguides, R.F. connectors, R.F. and microwave passive components and accessories.

The text of this standard is based on the following documents:

CDV	Report on voting
46F/242/CDV	46F/260/RVC

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

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- withdrawn,
- replaced by a revised edition, or
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## CYLINDRICAL CAVITY METHOD TO MEASURE THE COMPLEX PERMITTIVITY OF LOW-LOSS DIELECTRIC RODS

### 1 Scope

This International Standard relates to a measurement method for complex permittivity of a dielectric rod at microwave frequency. This method has been developed to evaluate the dielectric properties of low-loss materials in coaxial cables and electronic devices used in microwave systems. It uses the  $TM_{010}$  mode in a circular cylindrical cavity and presents accurate measurement results of a dielectric rod sample, where the effect of sample insertion holes is taken into account accurately on the basis of the rigorous electromagnetic analysis.

In comparison with the conventional method described in IEC 60556 [2]<sup>1</sup>, this method has the following characteristics:

- the values of the relative permittivity  $\epsilon'$  and loss tangent  $\tan\delta$  of a dielectric rod sample can be measured accurately and non-destructively;
- the measurement accuracy is within 1,0 % for  $\epsilon'$  and within 20 % for  $\tan\delta$ ;
- the effect of sample insertion holes is corrected using correction charts presented;
- this method is applicable for the measurements on the following condition:
  - frequency:  $1 \text{ GHz} \leq f \leq 10 \text{ GHz}$ ;
  - relative permittivity:  $1 \leq \epsilon' \leq 100$ ;
  - loss tangent:  $10^{-4} \leq \tan\delta \leq 10^{-1}$ .

### 2 Normative references

Void.

### 3 Measurement parameters

The measurement parameters are defined as follows:

$$\epsilon_r = \epsilon' - j\epsilon'' \quad (1)$$

$$\tan\delta = \epsilon''/\epsilon' \quad (2)$$

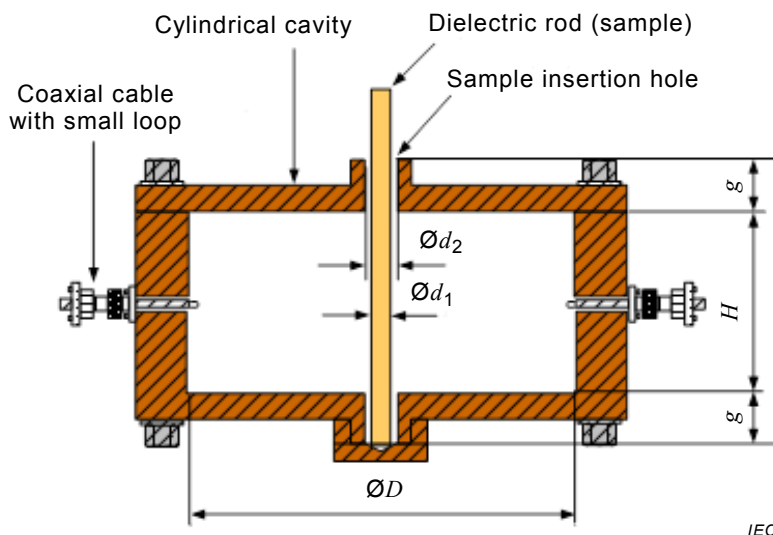
where  $\epsilon'$  and  $\epsilon''$  are the real and imaginary parts of the complex relative permittivity  $\epsilon_r$ .

### 4 Theory and calculation equations

A resonator structure used in these measurements is shown in Figure 1. A cavity, made with copper, with diameter  $D$  and height  $H$  has sample insertion holes with diameter  $d_2$  and depth  $g$  oriented coaxially. A dielectric rod sample of diameter  $d_1$  having  $\epsilon'$  and  $\tan\delta$  is inserted into the holes.

<sup>1</sup> Figures in square brackets refer to the Bibliography.

The  $TM_{010}$  mode, where the electric field component in the cavity is parallel to the sample rod, is used for the measurement. Taking account of the effect of sample insertion holes calculated on the basis of the rigorous electromagnetic field analysis,  $\varepsilon'$  and  $\tan\delta$  are determined from the measured values of the resonant frequency  $f_0$  and the unloaded  $Q$ -factor  $Q_u$ . To avoid the tedious numerical calculation and make the measurements easy, the following process is taken in this measurement:



**Figure 1 – Structure of a cylindrical cavity resonator**  
(standards.iteh.ai)

The following steps shall be taken:

- 1) At the first step, obtain approximate values  $\varepsilon_p$  and  $\tan\delta_p$  from the  $f_0$  and  $Q_u$  values by using the simple perturbation formulas, where the effect of sample insertion holes is neglected. The subscript p denotes the calculated values using the following perturbation formulas:

$$\varepsilon_p = \frac{1}{\alpha} \frac{f_0 - f_1}{f_1} \left( \frac{D}{d_1} \right)^2 + 1 \quad (3)$$

$$\tan\delta_p = \frac{1}{2\alpha\varepsilon_p} \left( \frac{D}{d_1} \right)^2 \left( \frac{1}{Q_{u1}} - \frac{1}{Q_{u0}} \right) \quad (4)$$

where  $\alpha = 1/J_1(x_{01})^2 = 1,855$ .

$J_n(x)$  is the Bessel function of order n of first kind and  $x_{01} = 2,405$  is the first root of  $J_0(x) = 0$ .  $f_0$  and  $Q_{u0}$  are the resonant frequency and unloaded  $Q$ -factor measured for the cavity without a sample, respectively.  $f_1$  and  $Q_{u1}$  are ones measured for the cavity with a sample.

- 2) In the second step, obtain accurate values  $\varepsilon'$  and  $\tan\delta$  from  $\varepsilon_p$  and  $\tan\delta_p$  values by using the following equations with correction factors calculated based on the rigorous analysis:

$$\varepsilon' = C_1 \varepsilon_p \quad (5)$$

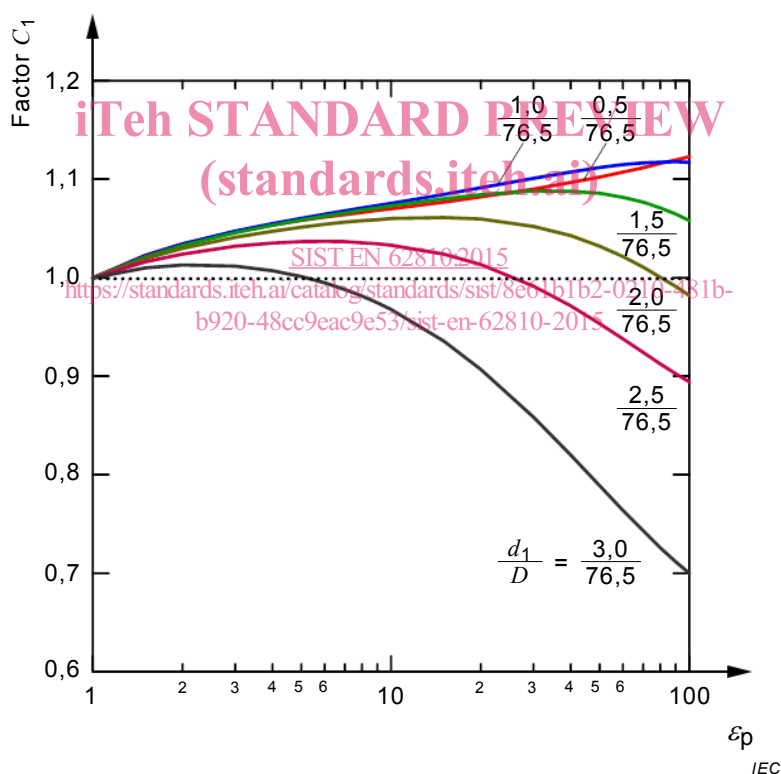
$$\tan\delta = C_2 \tan\delta_p \quad (6)$$

where correction factors  $C_1$  and  $C_2$ , due to the sample insertion holes and errors included in the perturbation formulas, are calculated numerically by using the Ritz-Galerkin method [3][5], as shown in Figure 2 and Figure 3, and the corresponding data are listed in detail in Table 1, 2, and 3. The missing data of  $C_1$  and  $C_2$  can be obtained by interpolation or extrapolation from the tables. The correction factors shown in these figures are calculated for the cavity with  $D = 76,5$  mm,  $H = 20,0$  mm,  $d_2 = 3,0$  mm, and  $g = 10,0$  mm, where the resonant frequency is about 3 GHz.  $C_1$  is also used for a cavity having the same aspect ratios as  $H/D$ ,  $d_2/D$  and  $g/D$ .

It is found from the analysis for a cavity with insertion holes which constitute a cut-off  $TM_{01}$  mode cylindrical waveguide that  $f_0$  converges to a constant value for  $g > 10$  mm and  $d_2 = 3$  mm. Therefore, the correction factors shown in Figure 2 and Figure 3 are applicable to a dielectric sample rod with  $d_1 < 3$  mm and  $\varepsilon'$  below the value calculated by the following equation for the measured value of the resonant frequency:

$$\varepsilon' \leq \left( \frac{x_{01}c}{\pi d_2 f_0} \right)^2 \quad (7)$$

where  $c$  is the velocity of light in a vacuum ( $c = 2,9979 \times 10^8$  m/s).



#### Assumptions

$D$	76,5 mm	$d_2$	3,0 mm
$H$	20,0 mm	$g$	10,0 mm

Figure 2 – Correction factor  $C_1$  for  $\varepsilon'$